



Integrated Device Technology, Inc.

CMOS STATIC RAM 16K (2K x 8 BIT)

IDT6116SA
IDT6116LA

FEATURES:

- High-speed access and chip select times
 - Military: 20/25/35/45/55/70/90/120/150ns (max.)
 - Commercial: 15/20/25/35/45ns (max.)
- Low-power consumption
- Battery backup operation
 - 2V data retention voltage (LA version only)
- Produced with advanced CMOS high-performance technology
- CMOS process virtually eliminates alpha particle soft-error rates
- Input and output directly TTL-compatible
- Static operation: no clocks or refresh required
- Available in ceramic and plastic 24-pin DIP, 24-pin Thin Dip and 24-pin SOIC and 24-pin SOJ
- Military product compliant to MIL-STD-883, Class B

DESCRIPTION:

The IDT6116SA/LA is a 16,384-bit high-speed static RAM organized as 2K x 8. It is fabricated using IDT's high-performance, high-reliability CMOS technology.

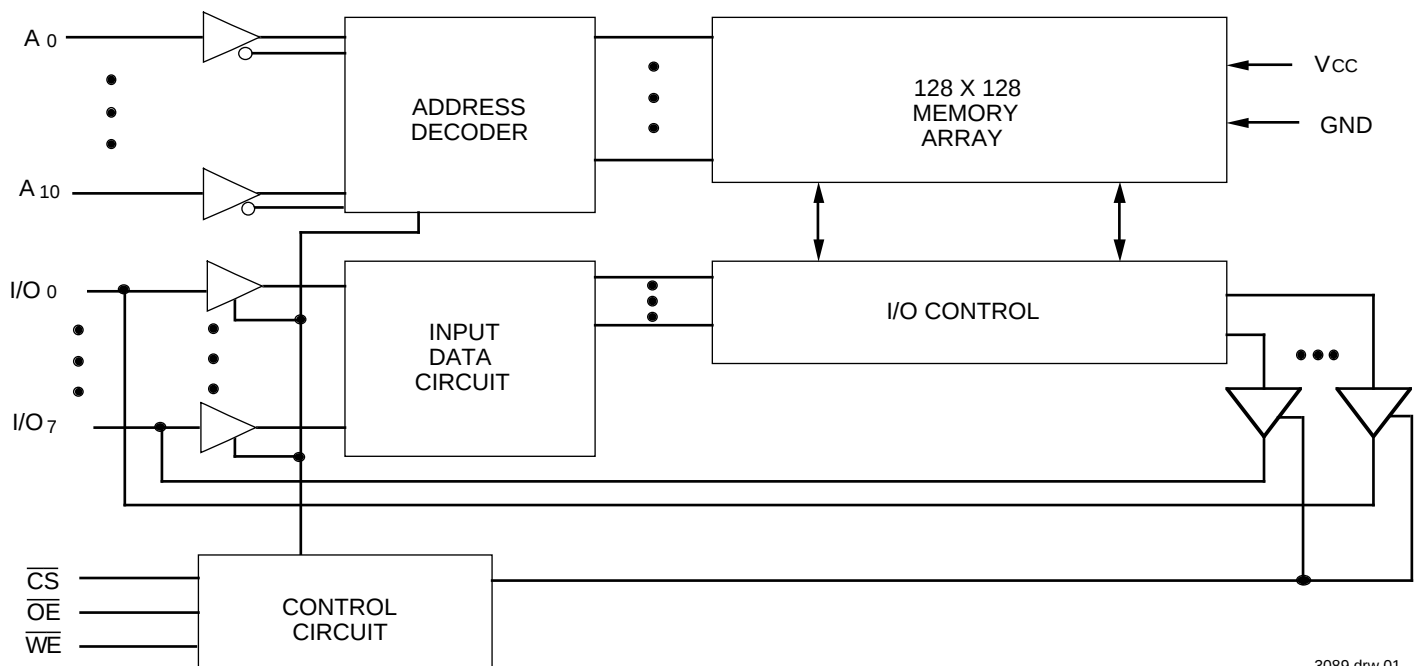
Access times as fast as 15ns are available. The circuit also offers a reduced power standby mode. When $\overline{CS}$ goes HIGH, the circuit will automatically go to, and remain in, a standby power mode, as long as $\overline{CS}$ remains HIGH. This capability provides significant system level power and cooling savings. The low-power (LA) version also offers a battery backup data retention capability where the circuit typically consumes only $1\mu W$ to $4\mu W$ operating off a 2V battery.

All inputs and outputs of the IDT6116SA/LA are TTL-compatible. Fully static asynchronous circuitry is used, requiring no clocks or refreshing for operation.

The IDT6116SA/LA is packaged in 24-pin 600 and 300 mil plastic or ceramic DIP and a 24-lead gull-wing SOIC, and a 24-lead J-bend SOJ providing high board-level packing densities.

Military grade product is manufactured in compliance to the latest version of MIL-STD-883, Class B, making it ideally suited to military temperature applications demanding the highest level of performance and reliability.

FUNCTIONAL BLOCK DIAGRAM



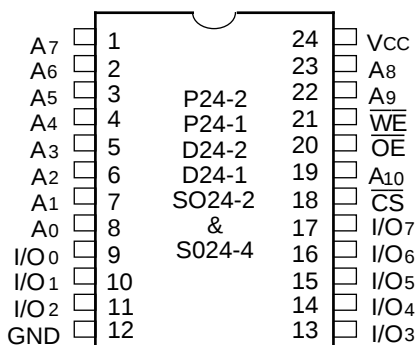
3089 drw 01

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MILITARY AND COMMERCIAL TEMPERATURE RANGES

MARCH 1996

PIN CONFIGURATIONS



3089 drw 02

DIP/SOIC/SOJ
TOP VIEW

PIN DESCRIPTIONS

A0–A13	Address Inputs
I/O0–I/O7	Data Input/Output
$\overline{CS}$	Chip Select
$\overline{WE}$	Write Enable
$\overline{OE}$	Output Enable
VCC	Power
GND	Ground

3089 tbl 01

CAPACITANCE (TA = +25°C, F = 1.0 MHz)

Symbol	Parameter ⁽¹⁾	Conditions	Max.	Unit
CIN	Input Capacitance	VIN = 0V	8	pF
CIO	I/O Capacitance	VOUT = 0V	8	pF

NOTE:

3089 tbl 03

1. This parameter is determined by device characterization, but is not production tested.

ABSOLUTE MAXIMUM RATINGS⁽¹⁾

Symbol	Rating	Commercial	Military	Unit
VTERM ⁽²⁾	Terminal Voltage with Respect to GND	–0.5 to + 7.0	–0.5 to +7.0	V
TA	Operating Temperature	0 to + 70	–55 to +125	°C
TBIAS	Temperature Under Bias	–55 to + 125	–65 to +135	°C
TSTG	Storage Temperature	–55 to + 125	–65 to +150	°C
PT	Power Dissipation	1.0	1.0	W
IOUT	DC Output Current	50	50	mA

NOTES:

3089 tbl 04

1. Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.
2. VTERM must not exceed VCC +0.5V.

TRUTH TABLE⁽¹⁾

Mode	$\overline{CS}$	$\overline{OE}$	$\overline{WE}$	I/O
Standby	H	X	X	High-Z
Read	L	L	H	DATAOUT
Read	L	H	H	High-Z
Write	L	X	L	DATAIN

NOTE:

3089 tbl 02

1. H = VIH, L = VIL, X = Don't Care.

RECOMMENDED OPERATING TEMPERATURE AND SUPPLY VOLTAGE

Grade	Ambient Temperature	GND	VCC
Military	-55°C to +125°C	0V	5.0V ± 10%
Commercial	0°C to +70°C	0V	5.0V ± 10%

3089 tbl 05

RECOMMENDED DC OPERATING CONDITIONS

Symbol	Parameter	Min.	Typ.	Max.	Unit
V _{CC}	Supply Voltage	4.5	5.0	5.5 ⁽²⁾	V
GND	Supply Ground	0	0	0	V
V _{IH}	Input High Voltage	2.2	3.5	V _{CC} + 0.5	V
V _{IL}	Input Low Voltage	-0.5 ⁽¹⁾	—	0.8	V

NOTES:

- V_{IL} (min.) = -3.0V for pulse width less than 20ns, once per cycle.
- V_{IH} must not exceed V_{CC} + 0.5V.

3089 tbl 06

DC ELECTRICAL CHARACTERISTICS

V_{CC} = 5.0V ± 10%

Symbol	Parameter	Test Conditions	IDT6116SA		IDT6116LA		Unit
			Min.	Max.	Min.	Max.	
I _{LI}	Input Leakage Current	V _{CC} = Max., V _{IN} = GND to V _{CC}	MIL.	—	10	—	5
			COM'L.	—	5	—	2
I _{LO}	Output Leakage Current	V _{CC} = Max. $\overline{CS} = V_{IH}$, V _{OUT} = GND to V _{CC}	MIL.	—	10	—	5
			COM'L.	—	5	—	2
V _{OL}	Output Low Voltage	I _{OL} = 8mA, V _{CC} = Min.	—	0.4	—	0.4	V
V _{OH}	Output High Voltage	I _{OH} = -4mA, V _{CC} = Min.	2.4	—	2.4	—	V

3089 tbl 07

DC ELECTRICAL CHARACTERISTICS ⁽¹⁾

V_{CC} = 5.0V ± 10%, V_{LC} = 0.2V, V_{HC} = V_{CC} - 0.2V

Symbol	Parameter	Power	6116SA15 ⁽²⁾ 6116LA15 ⁽²⁾		6116SA20 6116LA20		6116SA25 6116LA25		6116SA35 6116LA35		Unit
			Com'l.	Mil.	Com'l.	Mil.	Com'l.	Mil.	Com'l.	Mil.	
I _{CC1}	Operating Power Supply Current, $\overline{CS} \leq V_{IL}$, Outputs Open, V _{CC} = Max., f = 0	SA	105	—	105	130	80	90	80	90	mA
		LA	95	—	95	120	75	85	75	85	
I _{CC2}	Dynamic Operating Current, $\overline{CS} \leq V_{IL}$, V _{CC} = Max., Outputs Open, f = f _{MAX} ⁽⁴⁾	SA	150	—	130	150	120	135	100	115	mA
		LA	140	—	120	140	110	125	95	105	
I _{SB}	Standby Power Supply Current (TTL Level) $\overline{CS} \geq V_{IH}$, V _{CC} = Max., Outputs Open, f = f _{MAX} ⁽⁴⁾	SA	40	—	40	50	40	45	25	35	mA
		LA	35	—	35	45	35	40	25	30	
I _{SB1}	Full Standby Power Supply Current (CMOS Level), $\overline{CS} \geq V_{HC}$, V _{CC} = Max., V _{IN} ≥ V _{HC} or V _{IN} ≤ V _{LC} , f = 0	SA	2	—	2	10	2	10	2	10	mA
		LA	0.1	—	0.1	0.9	0.1	0.9	0.1	0.9	

NOTES:

- All values are maximum guaranteed values.
- 0°C to +70°C temperature range only.
- 55°C to +125°C temperature range only.
- f_{MAX} = 1/trc, only address inputs are cycling at f_{MAX}, f = 0 means address inputs are not changing.

3089 tbl 08

DC ELECTRICAL CHARACTERISTICS ⁽¹⁾ (Continued)

V_{CC} = 5.0V ± 10%, V_{LC} = 0.2V, V_{HC} = V_{CC} - 0.2V

Symbol	Parameter	Power	6116SA45 6116LA45		6116SA55 ⁽³⁾ 6116LA55 ⁽³⁾		6116SA70 ⁽³⁾ 6116LA70 ⁽³⁾		6116SA90 ⁽³⁾ 6116LA90 ⁽³⁾		6116SA120 ⁽³⁾ 6116LA120 ⁽³⁾		6116SA150 ⁽³⁾ 6116LA150 ⁽³⁾		Unit
			Com'l.	Mil.	Com'l.	Mil.	Com'l.	Mil.	Com'l.	Mil.	Com'l.	Mil.	Com'l.	Mil.	
I _{CC1}	Operating Power Supply Current, $\overline{CS} \leq V_{IL}$, Outputs Open, V _{CC} = Max., f = 0	SA	80	90	—	90	—	90	—	90	—	90	—	90	mA
		LA	75	85	—	85	—	85	—	85	—	85	—	85	
I _{CC2}	Dynamic Operating Current, $\overline{CS} \leq V_{IL}$, V _{CC} = Max., Outputs Open, f = f _{MAX} ⁽⁴⁾	SA	100	100	—	100	—	100	—	100	—	100	—	90	mA
		LA	90	95	—	90	—	90	—	85	—	85	—	85	
I _{SB}	Standby Power Supply Current (TTL Level) $\overline{CS} \geq V_{IH}$, V _{CC} = Max., Outputs Open, f = f _{MAX} ⁽⁴⁾	SA	25	25	—	25	—	25	—	25	—	25	—	25	mA
		LA	20	20	—	20	—	20	—	25	—	15	—	15	
I _{SB1}	Full Standby Power Supply Current (CMOS Level), $\overline{CS} \geq V_{HC}$, V _{CC} = Max., V _{IN} ≥ V _{HC} or V _{IN} ≤ V _{LC} , f = 0	SA	2	10	—	10	—	10	—	10	—	10	—	10	mA
		LA	0.1	0.9	—	0.9	—	0.9	—	0.9	—	0.9	—	0.9	

NOTES:

1. All values are maximum guaranteed values.
2. 0°C to + 70°C temperature range only.
3. -55°C to + 125°C temperature range only.
4. f_{MAX} = 1/trc, only address inouts are toggling at f_{MAX}, f = 0 means address inputs are not changing.

3089 tbl 09

DATA RETENTION CHARACTERISTICS OVER ALL TEMPERATURE RANGES

(LA Version Only) V_{LC} = 0.2V, V_{HC} = V_{CC} - 0.2V

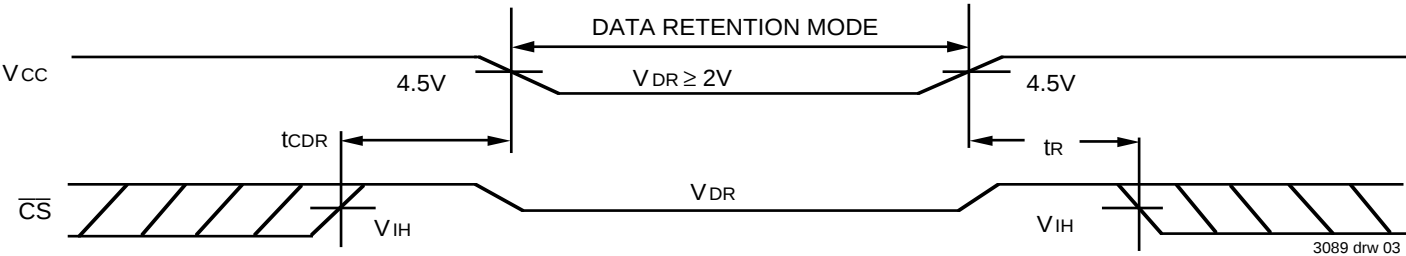
Symbol	Parameter	Test Conditions		Min.	Typ. ⁽¹⁾		Max.		Unit
					V _{CC}		V _{CC}		
					2.0V	3.0V	2.0V	3.0V	
V _{DR}	V _{CC} for Data Retention	—		2.0	—	—	—	—	V
I _{CCDR}	Data Retention Current	$\overline{CS} \geq V_{HC}$	MIL.	—	0.5	1.5	200	300	μA
			COM'L.	—	0.5	1.5	20	30	
t _{CDR} ⁽³⁾	Data Deselect to Data Retention Time	$V_{IN} \geq V_{HC}$ or $\leq V_{LC}$		—	0	—	—	—	ns
t _R ⁽³⁾	Operation Recovery Time			t _{RC} ⁽²⁾		—	—	—	—
I _{LI}	Input Leakage Current			—	—	—	2	2	μA

NOTES:

1. T_A = + 25°C
2. t_{RC} = Read Cycle Time.
3. This parameter is guaranteed by device characterization, but is not production tested.

3089 tbl 10

LOW VCC DATA RETENTION WAVEFORM



AC TEST CONDITIONS

Input Pulse Levels	GND to 3.0V
Input Rise/Fall Times	5ns
Input Timing Reference Levels	1.5V
Output Reference Levels	1.5V
AC Test Load	See Figures 1 and 2

3089 tbl 11

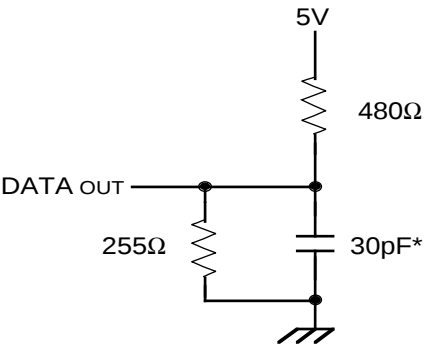


Figure 1. AC Test Load

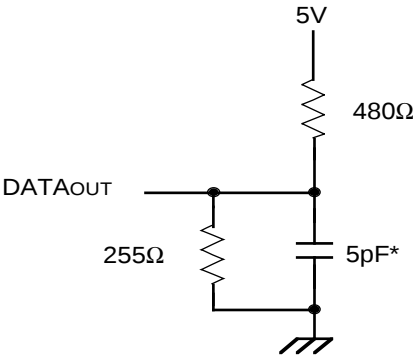


Figure 2. AC Test Load
(for tOLZ, tCLZ, tOHZ,
tWHZ, tCHZ & tOW)

*Including scope and jig.

AC ELECTRICAL CHARACTERISTICS (V_{CC} = 5V ± 10%, All Temperature Ranges)

Symbol	Parameter	6116SA15 ⁽¹⁾ 6116LA15 ⁽¹⁾		6116SA20 6116LA20		6116SA25 6116LA25		6116SA35 6116LA35		Unit
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
READ CYCLE										
tRC	Read Cycle Time	15	—	20	—	25	—	35	—	ns
tAA	Address Access Time	—	15	—	19	—	25	—	35	ns
tACS	Chip Select Access Time	—	15	—	20	—	25	—	35	ns
tCLZ ⁽³⁾	Chip Select to Output in Low-Z	5	—	5	—	5	—	5	—	ns
tOE	Output Enable to Output Valid	—	10	—	10	—	13	—	20	ns
tOLZ ⁽³⁾	Output Enable to Output in Low-Z	0	—	0	—	5	—	5	—	ns
tCHZ ⁽³⁾	Chip Deselect to Output in High-Z	—	10	—	11	—	12	—	15	ns
tOHZ ⁽³⁾	Output Disable to Output in High-Z	—	8	—	8	—	10	—	13	ns
tOH	Output Hold from Address Change	5	—	5	—	5	—	5	—	ns
tPU ⁽³⁾	Chip Select to Power-Up Time	0	—	0	—	0	—	0	—	ns
tPD ⁽³⁾	Chip Deselect to Power-Down Time	—	15	—	20	—	25	—	35	ns

3089 tbl 12

AC ELECTRICAL CHARACTERISTICS (V_{CC} = 5V ± 10%, All Temperature Ranges) (Continued)

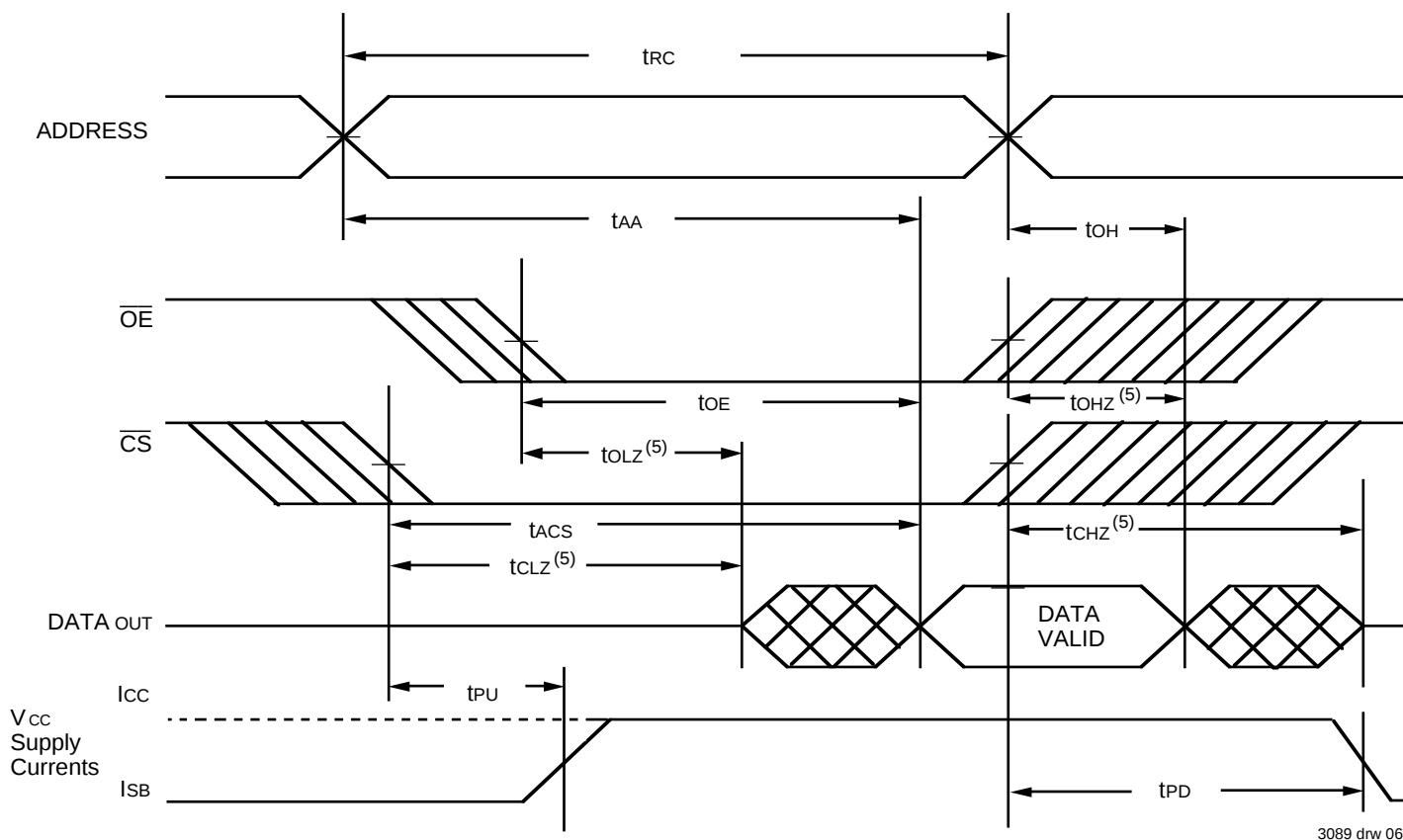
Symbol	Parameter	6116SA45 6116LA45		6116SA55 ⁽²⁾ 6116LA55 ⁽²⁾		6116SA70 ⁽²⁾ 6116LA70 ⁽²⁾		6116SA90 ⁽²⁾ 6116LA90 ⁽²⁾		6116SA120 ⁽²⁾ 6116LA120 ⁽²⁾		6116SA150 ⁽²⁾ 6116LA150 ⁽²⁾		Unit
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
READ CYCLE														
trc	Read Cycle Time	45	—	55	—	70	—	90	—	120	—	150	—	ns
tAA	Address Access Time	—	45	—	55	—	70	—	90	—	120	—	150	ns
tACS	Chip Select Access Time	—	45	—	50	—	65	—	90	—	120	—	150	ns
tCLZ ⁽³⁾	Chip Select to Output in Low-Z	5	—	5	—	5	—	5	—	5	—	5	—	ns
tOE	Output Enable to Output Valid	—	25	—	40	—	50	—	60	—	80	—	100	ns
tOLZ ⁽³⁾	Output Enable to Output in Low-Z	5	—	5	—	5	—	5	—	5	—	5	—	ns
tCHZ ⁽³⁾	Chip Deselect to Output in High-Z	—	20	—	30	—	35	—	40	—	40	—	40	ns
tOHZ ⁽³⁾	Output Disable to Output in High-Z	—	15	—	30	—	35	—	40	—	40	—	40	ns
tOH	Output Hold from Address Change	5	—	5	—	5	—	5	—	5	—	5	—	ns

NOTES:

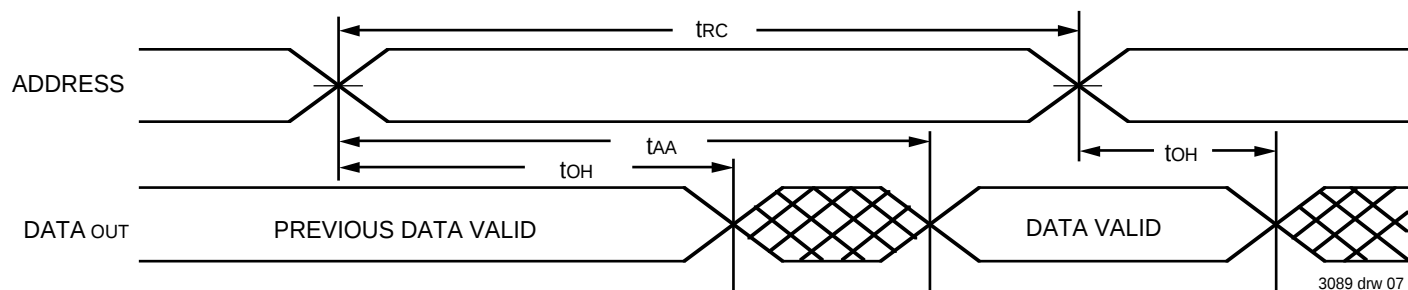
- 0°C to + 70°C temperature range only.
- 55°C to + 125°C temperature range only.
- This parameter guaranteed with the AC Load (Figure 2) by device characterization, but is not production tested.

3089 tbl 13

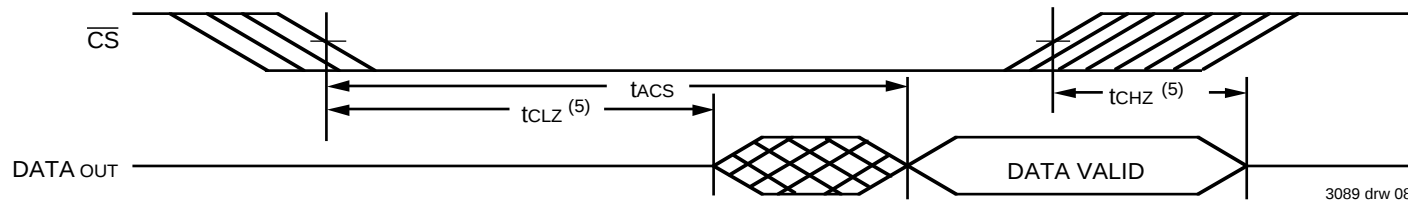
TIMING WAVEFORM OF READ CYCLE NO. 1^(1, 3)



TIMING WAVEFORM OF READ CYCLE NO. 2^(1, 2, 4)



TIMING WAVEFORM OF READ CYCLE NO. 3^(1, 3, 4)



NOTES:

1. $\overline{WE}$ is HIGH for Read cycle.
2. Device is continuously selected, $\overline{CS}$ is LOW.
3. Address valid prior to or coincident with $\overline{CS}$ transition LOW.
4. $\overline{OE}$ is LOW.
5. Transition is measured $\pm 500\text{mV}$ from steady state.

AC ELECTRICAL CHARACTERISTICS (V_{CC} = 5V ± 10%, All Temperature Ranges)

Symbol	Parameter	6116SA15 ⁽¹⁾ 6116LA15 ⁽¹⁾		6116SA20 6116LA20		6116SA25 6116LA25		6116SA35 6116LA35		Unit
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
WRITE CYCLE										
t _{WC}	Write Cycle Time	15	—	20	—	25	—	35	—	ns
t _{CW}	Chip Select to End-of-Write	13	—	15	—	17	—	25	—	ns
t _{AW}	Address Valid to End-of-Write	14	—	15	—	17	—	25	—	ns
t _{AS}	Address Set-up Time	0	—	0	—	0	—	0	—	ns
t _{WP}	Write Pulse Width	12	—	12	—	15	—	20	—	ns
t _{WR}	Write Recovery Time	0	—	0	—	0	—	0	—	ns
t _{WHZ} ⁽³⁾	Write to Output in High-Z	—	7	—	8	—	16	—	20	ns
t _{DW}	Data to Write Time Overlap	12	—	12	—	13	—	15	—	ns
t _{DH} ⁽⁴⁾	Data Hold from Write Time	0	—	0	—	0	—	0	—	ns
t _{OW} ^(3,4)	Output Active from End-of-Write	0	—	0	—	0	—	0	—	ns

3089 tbl 14

AC ELECTRICAL CHARACTERISTICS (V_{CC} = 5V ± 10%, All Temperature Ranges)

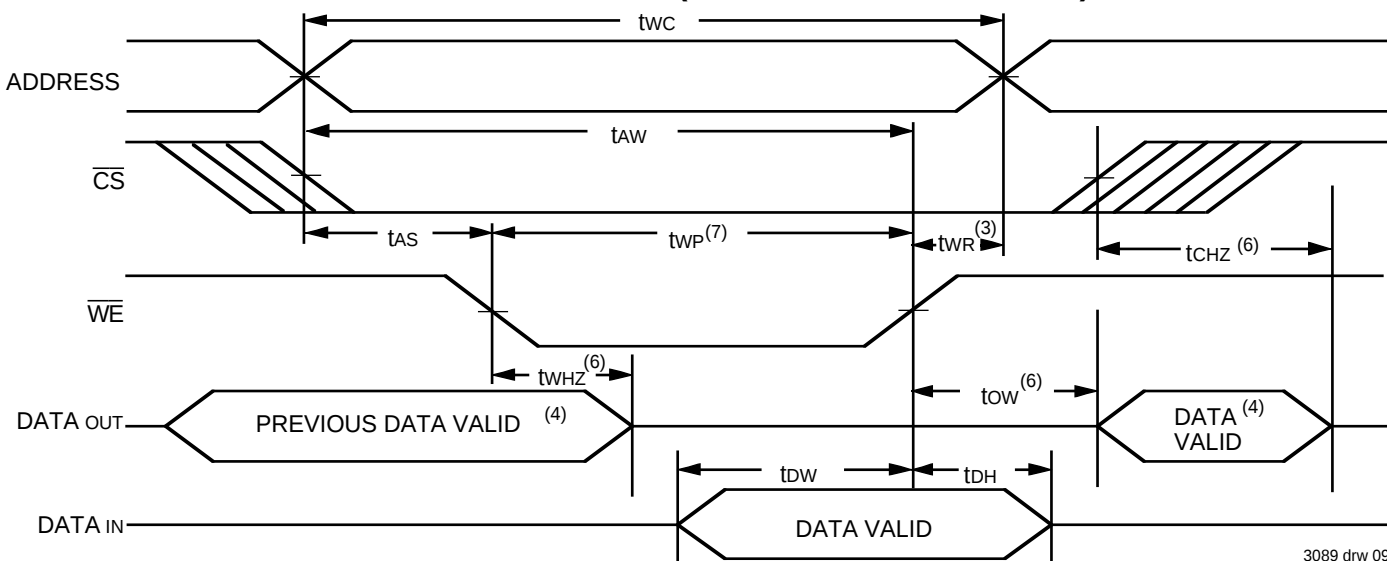
Symbol	Parameter	6116SA45 6116LA45		6116SA55 ⁽²⁾ 6116LA55 ⁽²⁾		6116SA70 ⁽²⁾ 6116LA70 ⁽²⁾		6116SA90 ⁽²⁾ 6116LA90 ⁽²⁾		6116SA120 ⁽²⁾ 6116LA120 ⁽²⁾		6116SA150 ⁽²⁾ 6116LA150 ⁽²⁾		Unit
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
WRITE CYCLE														
t _{WC}	Write Cycle Time	45	—	55	—	70	—	90	—	120	—	150	—	ns
t _{CW}	Chip Select to End of Write	30	—	40	—	40	—	55	—	70	—	90	—	ns
t _{AW}	Address Valid to End of Write	30	—	45	—	65	—	80	—	105	—	120	—	ns
t _{AS}	Address Set-up Time	0	—	5	—	15	—	15	—	20	—	20	—	ns
t _{WP}	Write Pulse Width	25	—	40	—	40	—	55	—	70	—	90	—	ns
t _{WR}	Write Recovery Time	0	—	5	—	5	—	5	—	5	—	10	—	ns
t _{WHZ} ⁽³⁾	Write to Output in High-Z	—	25	—	30	—	35	—	40	—	40	—	40	ns
t _{DW}	Data to Write Time Overlap	20	—	25	—	30	—	30	—	35	—	40	—	ns
t _{DH} ⁽⁴⁾	Data Hold from Write Time	0	—	5	—	5	—	5	—	5	—	10	—	ns
t _{OW} ^(3,4)	Output Active from End of Write	0	—	0	—	0	—	0	—	0	—	0	—	ns

NOTES:

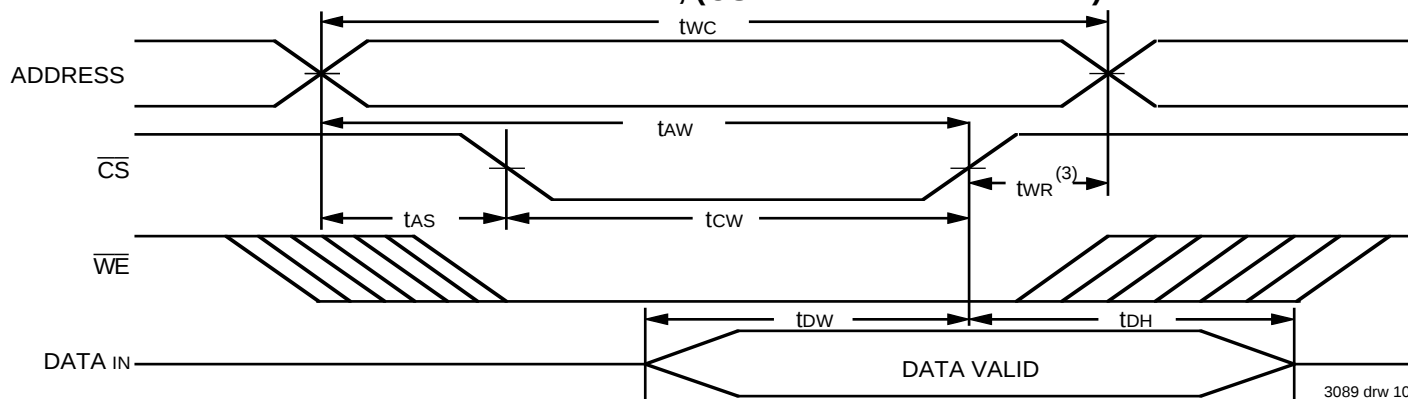
- 0°C to +70°C temperature range only.
- 55°C to +125°C temperature range only.
- This parameter guaranteed with AC Load (Figure 2) by device characterization, but is not production tested.
- The specification for t_{DH} must be met by the device supplying write data to the RAM under all operation conditions. Although t_{DH} and t_{OW} values will vary over voltage and temperature, the actual t_{DH} will always be smaller than the actual t_{OW}.

3089 tbl 15

TIMING WAVEFORM OF WRITE CYCLE NO. 1, ($\overline{WE}$ CONTROLLED TIMING) (1, 2, 5, 7)



TIMING WAVEFORM OF WRITE CYCLE NO. 2, ($\overline{CS}$ CONTROLLED TIMING) (1, 2, 3, 5, 7)



NOTES:

1. $\overline{WE}$ or $\overline{CS}$ must be HIGH during all address transitions.
2. A write occurs during the overlap of a LOW $\overline{CS}$ and a LOW $\overline{WE}$.
3. t_{WR} is measured from the earlier of $\overline{CS}$ or $\overline{WE}$ going HIGH to the end of the write cycle.
4. During this period, the I/O pins are in the output state and the input signals must not be applied.
5. If the $\overline{CS}$ LOW transition occurs simultaneously with or after the $\overline{WE}$ LOW transition, the outputs remain in the high-impedance state.
6. Transition is measured $\pm 500\text{mV}$ from steady state.
7. $\overline{OE}$ is continuously HIGH. If $\overline{OE}$ is LOW during a $\overline{WE}$ controlled write cycle, the write pulse width must be the larger of t_{WP} or $(t_{WHZ} + t_{OW})$ to allow the I/O drivers to turn off and data to be placed on the bus for the required t_{OW} . If $\overline{OE}$ is HIGH during a $\overline{WE}$ controlled write cycle, this requirement does not apply and the write pulse is the specified t_{WP} . For a $\overline{CS}$ controlled write cycle, $\overline{OE}$ may be LOW with no degradation to t_{CW} .

ORDERING INFORMATION

IDT	6116	XX	XXX	X	X	
	Device Type	Power	Speed	Package	Process/ Temperature Range	
					Blank	Commercial (0°C to +70°C)
					B	Military (-55°C to + 125°C) Compliant to MIL-STD-883, Class B
					TP	300 mil Plastic DIP (P24-1)
					P	600 mil Plastic DIP (P24-2)
					TD	300 mil CERDIP (D24-1)
					D	600 mil CERDIP (D24-2)
					SO	300 mil Small Outline IC, Gull-Wing Bend (SO24-2)
					Y	300 mil SOJ, J-Bend (SO24-4)
					15	Commercial Only
					20	
					25	
					35	
					45	
					55	Military Only
					70	
					90	
					120	
					150	
					SA	Standard Power
					LA	Low Power

Speed in nanoseconds

3089 drw 11